

**Search Notes**

Application/Control No.

10/723,283

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

FABRITIUS, HENNA

Art Unit

2174

**SEARCHED**

Class	Subclass	Date	Examiner
715	702	3/29/2007	LEE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	as above	3/29/2007	LEE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
s. sax	3/29/2007	LEE